

### SEMiX<sup>®</sup> 3p

### Trench IGBT Modules

### SEMiX603GAL17E4p

#### Features\*

- Homogeneous Si
- Trench = Trenchgate technology
   V<sub>CE(sat)</sub> with positive temperature
- coefficient
- High short circuit capability
- Press-fit pins as auxiliary contacts
- UL recognized, file no. E63532

### **Typical Applications**

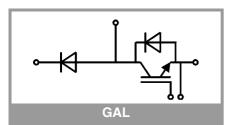
- AC inverter drives
- UPS
- Renewable energy systems

### Remarks

- Product reliability results are valid for  $T_i=150^{\circ}C$
- V<sub>isol</sub> between temperature sensor and power section is only 2500V
- For storage and case temperature with TIM see document "TP(\*) SEMiX 3p"

	Maximum Ratin	3-		1
Symbol	Conditions		Values	Unit
IGBT				
V <sub>CES</sub>	T <sub>j</sub> = 25 °C		1700	V
I <sub>C</sub>	T <sub>i</sub> = 175 °C	T <sub>c</sub> = 25 °C	835	А
		T <sub>c</sub> = 80 °C	638	А
I <sub>Cnom</sub>			600	А
I <sub>CRM</sub>			1800	A
V <sub>GES</sub>			-20 20	V
t <sub>psc</sub>	$V_{CC} = 1000 V$ $V_{GE} \le 15 V$ $V_{CES} \le 1700 V$	T <sub>j</sub> = 150 °C	10	μs
Tj			-40 175	°C
Inverse di	iode	·		
V <sub>RRM</sub>	T <sub>i</sub> = 25 °C		1700	V
l <sub>F</sub>	T <sub>j</sub> = 175 °C	T <sub>c</sub> = 25 °C	736	Α
		T <sub>c</sub> = 80 °C	542	А
I <sub>FRM</sub>			1200	А
I <sub>FSM</sub>	$t_p = 10 \text{ ms}, \sin 180^\circ, T_j = 25 ^\circ\text{C}$		3510	Α
Tj			-40 175	°C
Freewhee	ling diode			<b>!</b>
V <sub>RRM</sub>	T <sub>j</sub> = 25 °C		1700	V
l <sub>F</sub>	T <sub>j</sub> = 175 °C	T <sub>c</sub> = 25 °C	703	А
		T <sub>c</sub> = 80 °C	517	А
I <sub>FRM</sub>		I	1200	А
I <sub>FSM</sub>	t <sub>p</sub> = 10 ms, sin 18	0°, T <sub>j</sub> = 25 °C	3510	А
Tj			-40 175	°C
Module	1			R
I <sub>t(RMS)</sub>			600	A
T <sub>stg</sub>	module without TIM		-40 125	
V <sub>isol</sub>	AC sinus 50Hz, t = 1 min		4000	

Characte	eristics					
Symbol	Conditions		min.	typ.	max.	Unit
IGBT	•					
V <sub>CE(sat)</sub>	$I_{\rm C} = 600  {\rm A}$	T <sub>j</sub> = 25 °C		1.95	2.30	V
	V <sub>GE</sub> = 15 V chiplevel	T <sub>j</sub> = 150 °C		2.48	2.80	V
V <sub>CE0</sub>	chiplevel	T <sub>j</sub> = 25 °C		1.02	1.20	V
	chipievei	T <sub>j</sub> = 150 °C		0.92	1.03	V
r <sub>CE</sub>	V <sub>GE</sub> = 15 V	T <sub>j</sub> = 25 °C		1.55	1.83	mΩ
	chiplevel	T <sub>j</sub> = 150 °C		2.6	3.0	mΩ
V <sub>GE(th)</sub>	$V_{GE} = V_{CE}, I_C = 24 \text{ mA}$		5.2	5.8	6.2	V
I <sub>CES</sub>	$V_{GE} = 0 V, V_{CE} = 1700 V, T_j = 25 °C$				5	mA
Cies	V <sub>CE</sub> = 25 V V <sub>GE</sub> = 0 V	f = 1 MHz		46.5		nF
Coes		f = 1 MHz		1.98		nF
C <sub>res</sub>		f = 1 MHz		1.65		nF
Q <sub>G</sub>	V <sub>GE</sub> = - 8 V+ 15 V			4800		nC
R <sub>Gint</sub>	$T_j = 25 \ ^{\circ}C$			1.1		Ω





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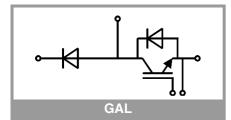
### **Typical Applications**

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- UPS
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- Product reliability results are valid for  $T_{j=150^{\circ}C}$
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Characte	ristics					
Symbol	Conditions		min.	typ.	max.	Unit
IGBT						
t <sub>d(on)</sub>	V <sub>CC</sub> = 900 V	T <sub>i</sub> = 150 °C		245		ns
t <sub>r</sub>	$I_{\rm C} = 600  {\rm A}$	T <sub>i</sub> = 150 °C		85		ns
Eon	$V_{GE} = +15/-15 V$ $R_{G on} = 2.4 \Omega$	T <sub>i</sub> = 150 °C		132		mJ
t <sub>d(off)</sub>	$R_{G off} = 1 \Omega$	T <sub>i</sub> = 150 °C		710		ns
t <sub>f</sub>	di/dt <sub>on</sub> = 7900 A/µs	T <sub>i</sub> = 150 °C		170		ns
E <sub>off</sub>	$\begin{array}{l} \text{di/dt}_{\text{off}} = 3000 \text{ A/}\mu\text{s} \\ \text{dv/dt} = 3500 \text{ V/}\mu\text{s} \\ \text{L}_{\text{s}} = 25 \text{ nH} \end{array}$	T <sub>j</sub> = 150 °C		213		mJ
R <sub>th(j-c)</sub>	per IGBT				0.049	K/W
R <sub>th(c-s)</sub>	per IGBT ( $\lambda_{grease}=0$	.81 W/(m*K))		0.033		K/W
R <sub>th(c-s)</sub>	per IGBT, pre-appli material	ed phase change		0.023		K/W
Inverse di	iode					
$V_F = V_{EC}$	$I_{\rm F} = 600  {\rm A}$	T <sub>j</sub> = 25 °C		1.88	2.23	V
	V <sub>GE</sub> = 0 V chiplevel	T <sub>j</sub> = 150 °C		1.95	2.32	V
V <sub>F0</sub>		T <sub>i</sub> = 25 °C		1.32	1.56	V
	chiplevel	T <sub>i</sub> = 150 °C		1.08	1.22	V
r <sub>F</sub>		T <sub>i</sub> = 25 °C		0.93	1.12	mΩ
	- chiplevel	T <sub>i</sub> = 150 °C		1.45	1.83	mΩ
I <sub>RRM</sub>	I <sub>F</sub> = 600 A	T; = 150 °C		700		Α
Q <sub>rr</sub>	$di/dt_{off} = 8000 \text{ A/}\mu\text{s}$	T <sub>i</sub> = 150 °C		190		μC
E <sub>rr</sub>	V <sub>GE</sub> = -15 V V <sub>CC</sub> = 900 V	T <sub>i</sub> = 150 °C		125		mJ
R <sub>th(j-c)</sub>	per diode				0.082	K/W
R <sub>th(c-s)</sub>	per diode (λ <sub>grease</sub> =0	.81 W/(m*K))		0.038		K/W
R <sub>th(c-s)</sub>	per diode, pre-applied phase change material			0.030		K/W
Freewhee	ling diode					
$V_F = V_{EC}$	I <sub>F</sub> = 600 A	T <sub>j</sub> = 25 °C		1.88	2.23	V
	V <sub>GE</sub> = 0 V chiplevel	T <sub>j</sub> = 150 °C		1.95	2.32	V
V <sub>F0</sub>		T <sub>i</sub> = 25 °C		1.32	1.56	V
-10	chiplevel	T <sub>j</sub> = 150 °C		1.08	1.22	V
۲ <sub>F</sub>		T <sub>i</sub> = 25 °C		0.93	1.12	mΩ
	chiplevel	T <sub>i</sub> = 150 °C		1.45	1.83	mΩ
I <sub>RRM</sub>	I <sub>F</sub> = 600 A	T <sub>i</sub> = 150 °C		700		Α
Q <sub>rr</sub>	$di/dt_{off} = 8000 \text{ A/}\mu\text{s}$	T <sub>i</sub> = 150 °C		190		μC
E <sub>rr</sub>	V <sub>GE</sub> = -15 V V <sub>CC</sub> = 900 V	T <sub>i</sub> = 150 °C		125		mJ
R <sub>th(j-c)</sub>	per diode	, - ,			0.088	K/W
R <sub>th(c-s)</sub>	per diode ( $\lambda_{\text{grease}}=0$	.81 W/(m*K))		0.038	0.000	K/W
R <sub>th(c-s)</sub>	per diode, pre-appl material			0.030		K/W





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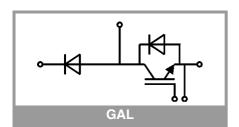
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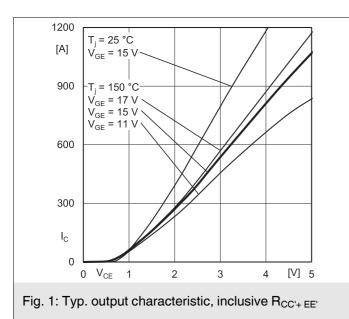
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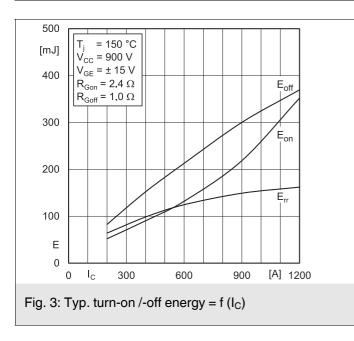
#### Remarks

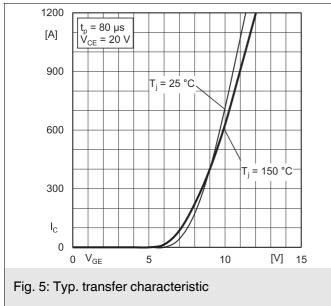
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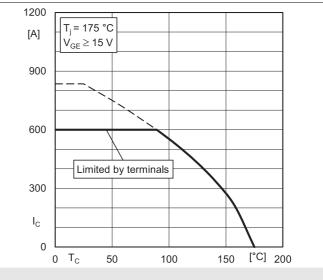
Characte	ristics					
Symbol	Conditions		min.	typ.	max.	Unit
Module						
L <sub>CE</sub>				20		nH
R <sub>CC'+EE'</sub>	measured per switch	T <sub>C</sub> = 25 °C		0.95		mΩ
		T <sub>C</sub> = 125 °C	1.25			mΩ
R <sub>th(c-s)1</sub>	calculated without thermal coupling 0.0		0.009		K/W	
R <sub>th(c-s)2</sub>	including thermal coupling, T <sub>s</sub> underneath module ( $\lambda_{grease}$ =0.81 W/ (m*K))			0.014		K/W
R <sub>th(c-s)2</sub>	including thermal coupling, $T_s$ underneath module, pre-applied phase change material			0.021		K/W
Ms	to heat sink (M5)		3		6	Nm
Mt		to terminals (M6)	3		6	Nm
						Nm
w					350	g
Temperat	ure Sensor					•
R <sub>100</sub>	T <sub>c</sub> =100°C (R <sub>25</sub> =5 kΩ)			493 ± 5%		Ω
B <sub>100/125</sub>	R <sub>(T)</sub> =R <sub>100</sub> exp[B <sub>100/125</sub> (1/T-1/T <sub>100</sub> )]; T[K];			3550 ±2%		к

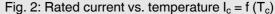


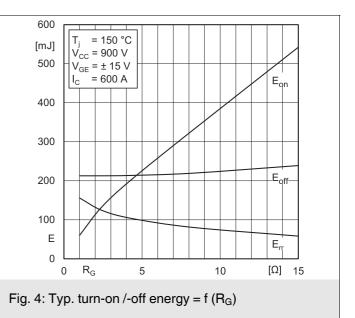


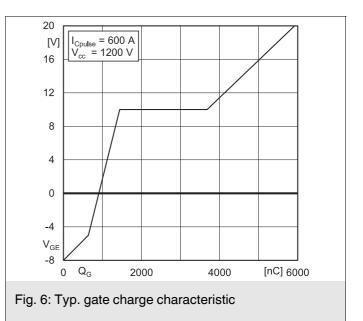




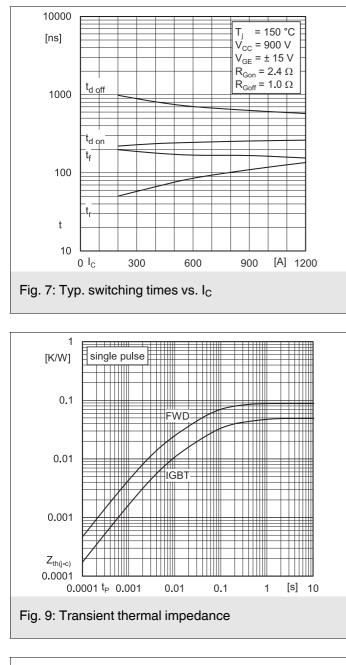


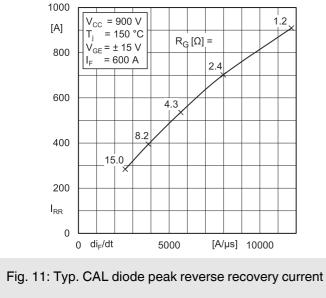


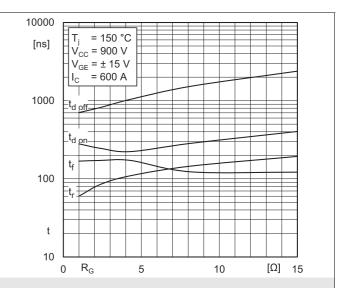


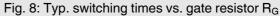


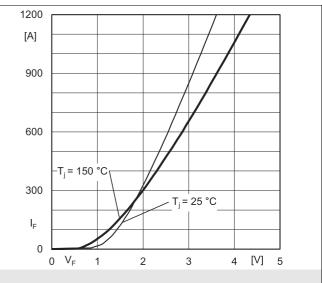
Rev. 1.0 – 14.04.2022

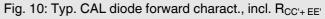


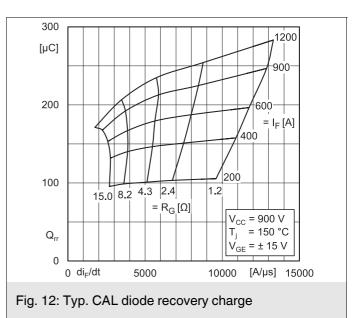


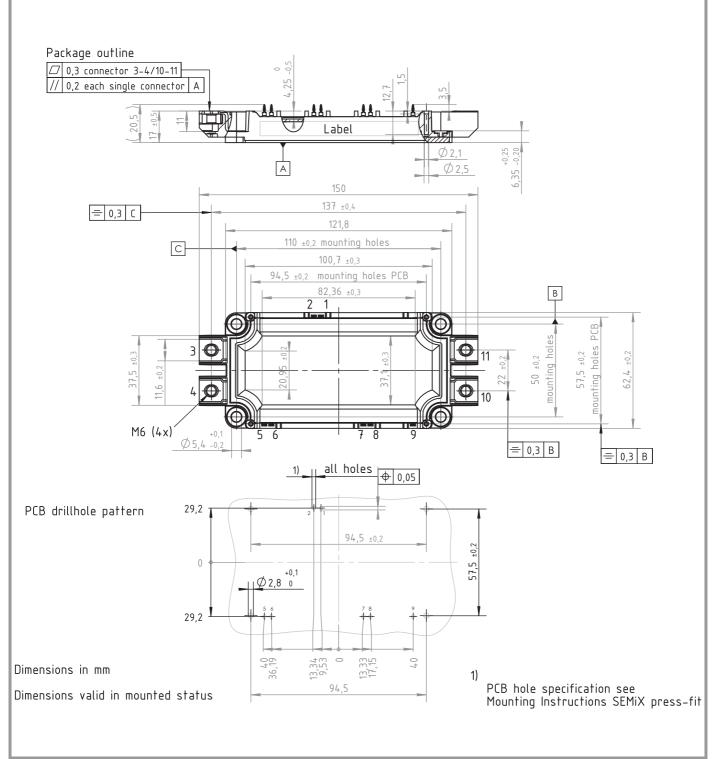




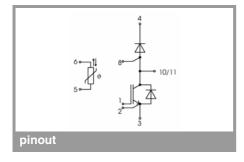








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This is an electrostatic discharge sensitive device (ESDS) due to international standard IEC 61340.

#### **\*IMPORTANT INFORMATION AND WARNINGS**

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